

AXA Series Other Test Reports Contents

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%A part of evaluation data is provided as an example.

We provide individual evaluation data of a particular product or unpublished data after a request by e-mail. please contact us individually for data not listed on the site.

Xindividual evaluation data of a particular product can be downloaded from the Product Search page.



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		Product : SD Memory Card Socket
Initial Contact Resistance	TEST REPORT	Data No. : AXA2S73062-M-001
		Page No. : 1/1
Purpose Confirm characteristics	of initial contact resi	stance in accordance with spec.
Sample SD Memory card socke Stand-off 0mm (With th <axa2s73062-m> (n=</axa2s73062-m>	ne function of card jur	9 S-type, Standard type) np-out prevention)
Test condition Measure the resistance		
(According to the meth		
SD memory card: Test	card (Made by Pana	sonic)
Criteria		
Contact resistance		Signal Contacts
Signal contacts: 100 r	mΩ max.	Card <u></u> Detection
Card detection contact	ts: 150 mΩ max.	Contacts
Write protect contacts	: 150 mΩ max.	
		Write Protect Contacts
Test result		
Signal contacts: 45 Co	ntacts, Detection con	acts: 15 contacts [mΩ

	Olemal anatosta	Detection contacts	
	Signal contacts	Card detection contacts	Write protect contacts
Avg.	16.050	41.750	33.683
Max.	19.79	42.26	35.02
Min.	13.50	41.25	32.14

Judgment

			Date: April 05, 2011
HONDA TSUSHIN KOGYO CO., LTD.	Drawn by	Tylege	Reviewed by -
	Checked by	T. Soto	Approved by K. Taleahasha

Insulation Res	sistance
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Confirm characteristics of insulation resistance in accordance with spec.

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

The insulation resistance between contiguity terminals (mating card) and between shell and each contact (unmating card) is measured. Measured at D.C. 500 V megger for 1 minute.

Criteria

Insulation resistance: 1,000MΩ min. (Initial)

Test result

Contiguity terminals: 50 contacts. Between shell and each contact: 60 contacts

Measurement part	Test result	
Contiguity terminals	More than 1,000MΩ	
Between shell and each contact		

Judgment

	Date: April 05, 2011		
HONDA TSUSHIN KOGYO CO., LTD.	Drawn by T-	Reviewed by	
	Checked by	to Approved by K. Tahahashi	

Breakdown Voltage Resistance	TEST
	Contraction of the second

Confirm characteristics of breakdown voltage resistance in accordance with spec.

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type.) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

The breakdown voltage resistance between contiguity terminals (mating card) and between shell and each contact (unmating card) is measured.

A.C. 500 V are impressed for 1 minute and it measure with 1mA of detection current.

Criteria

There are no short and damage.

Test result

Contiguity terminals: 50 contacts. Between shell and each contact: 60 contacts

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

Judgment

Date: April 05, 2011			5, 2011		
HONDA TSUSHIN KOGYO CO., LTD.	Drawn by	Tilege	Reviewed by		
	Checked by	-T. Sata	Approved by	K. Takohathi	

Card	Insertion and
	Removal Force

Purpose

Confirm characteristics of card insertion and removal force in accordance with spec.

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type,) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

It measures with an exclusive examination machine. SD memory card: Test card (Made by Panasonic)

Criteria

Card insertion force: 40N max. Card removal force: 1N min. 40N max.

Test result

		[N
	Card insertion force	Card removal force
Avg.	9.658	9.581
Max.	9.90	9.86
Min.	9.28	9.37

>Card insertion force: The load for cum-lock

>Card removal force: The load for cum-unlock

Judgment

		-	Date: April 0	5, 2011	
	Drawn by	T- lege	Reviewed by		
HONDA TSUSHIN KOGYO CO., LTD.	Checked by	-Tslato	Approved by	K. Takahashi	

Confirm characteristics of resistant to soldering heat (reflow soldering) in accordance with spec.

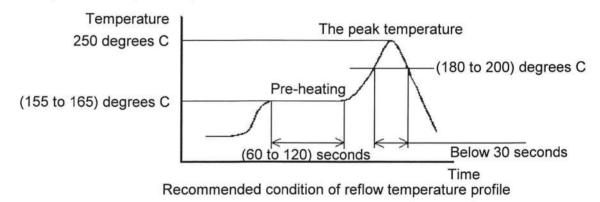
Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

Reflow solder

- 1) Used solder: M705 (Made by SENJU METAL INDUSTRY CO., LTD.)
- 2) Screen thickness: 120µm
- 3) P.C.B. thickness: 1.0mm (FR-4)
- 4) Reflow temperature profile:



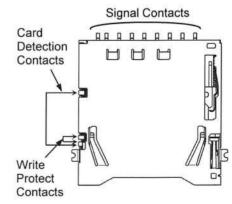
Criteria

After 2 times reflow

- a) Appearance: There is no deforming, camber and crack of molded parts.
- b) Insulation resistance: 1,000 M Ω min. (at D.C. 500 V)
- c) Breakdown voltage resistance: A.C. 500 V / 1 minute. (Detection current: 1mA)
- d) Contact resistance:

Signal contacts: $100m\Omega$. Card detection contacts: $150m\Omega$ min. Write protect contacts: $150m\Omega$ min.

- e) Card insertion force: 40N max.
- f) Card removal force: 1N min. 40N max.



			Date: April 08	5, 2011
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	Checked by	T. Salo	Approved by	K. Takabashi

2/2

Test result

a) Appearance: There was no deforming, camber and crack of molded parts.

b) Insulation resistance:

Measurement part	Test result	
Contiguity terminals	More then 1 000 MO	
Between shell and each contact	More than 1,000 M Ω	

Page No. :

c) Breakdown voltage resistance:

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

d) Contact resistance:

Detection contacts Signal contacts Card detection contacts Write protect contacts Avg. 42.382 34.208 15.988 Max. 20.99 43.66 34.84 Min. 13.75 40.83 33.73

e) Card insertion force:

Card insertion force:		[N]
	Test result	
Avg.	9.632	
Max.	9.97	
Min.	9.25	

f) Card remo	oval force:
--------------	-------------

/	Test result	
Avg.	9.663	
Max.	9.93	
Min.	Min. 9.37	

Judgment

No problems were observed.

	Date: April 05, 2011
HONDA TSUSHIN KOGYO CO., LTD.	

[mΩ]

[N]

Confirm characteristics of resistant to soldering heat (manual soldering) in accordance with spec.

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

Manual solder

- 1) Used solder: M705 (Made by SENJU METAL INDUSTRY CO., LTD.)
- 2) P.C.B. thickness: 1.0mm (FR-4)
- Soldering condition: Soldering iron temperature: 300 degrees C

Soldering time: 5 seconds

Criteria

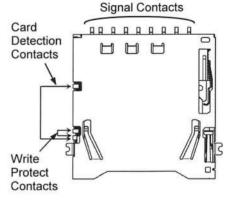
After manual solder

- a) Appearance: There is no deforming, camber and crack of molded parts.
- b) Insulation resistance: 1,000 M Ω min. (at D.C. 500 V)
- c) Breakdown voltage resistance: A.C. 500 V / 1 minute. (Detection current: 1mA)
- d) Contact resistance:

Signal contacts: $100m\Omega$. Card detection contacts: $150m\Omega$ min. Write protect contacts: $150m\Omega$ min.

e) Card insertion force: 40N max.

f) Card removal force: 1N min. 40N max.



Test result

a) Appearance: There was no deforming, camber and crack of molded parts.

b) Insulation resistance:

Measurement part	Test result	
Contiguity terminals	More then 1 000 MO	
Between shell and each contact	More than 1,000 $M\Omega$	

c) Breakdown voltage resistance:

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

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	Drawn by	Tilege	Reviewed by	
HONDA TSUSHIN KOGYO CO., LTD.	Checked by	T.Sat	Approved by	K. Talahadhi

[N]

d) Contact resistance:

Contact	resistance:		[mΩ	
	Signal contacts	Detection contacts		
	Signal contacts	Card detection contacts	Write protect contacts	
Avg.	12.281	44.081	31.906	
Max.	20.71	45.13	33.20	
Min.	15.85	42.22	30.26	

e) Card insertion force:

	Test result	
Avg.	9.730	
Max.	10.25	
Min.	9.31	

f) Card removal force: [N] Test result Avg. 9.513 Max. 9.93 Min. 9.11

Judgment

	Date: April 05, 2011	
HONDA TSUSHIN KOGYO CO., LTD.		

Resistant to Humidity

Confirm characteristics of resistant to humidity in accordance with spec.

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type,) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

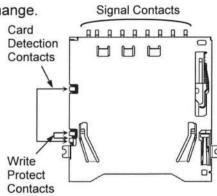
Temperature: +40 degrees C Humidity of the upper limit: 95%RH Humidity of the lower limit: 90%RH Exposure condition: Mating card

Criteria

- After 500 hours exposure
- a) Appearance: There is no deforming, camber and crack of molded parts.
- b) Insulation resistance: 100 M Ω min. (at D.C. 500 V)
- c) Breakdown voltage resistance: A.C. 500 V / 1 minute. (Detection current: 1mA)

d) Contact resistance: Signal contacts: After test 40mΩ maximum change. Card detection contacts: 150mΩ min. Write protect contacts: 150mΩ min.

- e) Card insertion force: 40N max.
- f) Card removal force: 1N min. 40N max.



Test result

a) Appearance: There was no deforming, camber and crack of molded parts.

b) Insulation resistance:

Measurement part	Test result	
Contiguity terminals	More than 100 M Ω	
Between shell and each contact	More than 100 Mtz	

c) Breakdown voltage resistance:

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

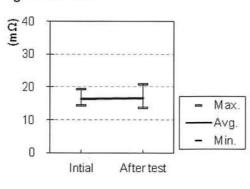
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	Checked by	T. Salo	Approved by	K. Takahashi	

Data No. : AXA2S73062-M-010

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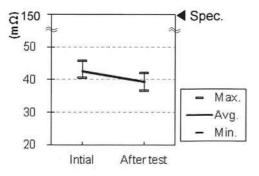
2/2

d) Contact resistance: Signal contacts

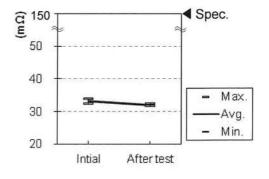


⊿Rc	[mΩ]
Avg.	0.292
Max.	3.10
Min.	-2.22

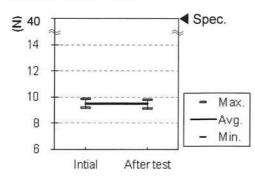
Card detection contacts



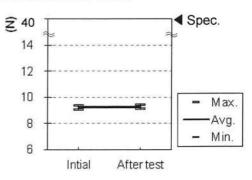
Write protect contacts



e) Card insertion force:



g) Card removal force:



Judgment

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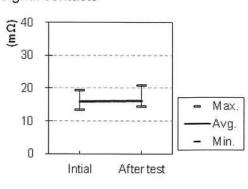
		Product : SD Memory Card Socket				
Thermal Shock	TEST REPORT	Data No. : AXA2S73062-M-011				
Resisitance		Page No.: 1/2				
Purpose Confirm characteristics	of thermal shock resi	istance in accordance with spec.				
SD Memory card socke Stand-off 0mm (With th <axa2s73062-m> (n=</axa2s73062-m>	ne function of card jun	S-type, Standard type,) np-out prevention)				
Test condition						
Temperature of the upp Temperature of the low Time: 30 minutes each Exposure condition: Ma	ver limit: -55 degrees (
b) Insulation resistance c) Breakdown voltage d) Contact resistance: Signal contacts: A Card detection co Write protect com e) Card insertion force f) Card removal force:	e is no deforming, cam e: 100 MΩ min. (at D. resistance: A.C. 500 After test 40mΩ maxin ontacts: 150mΩ min. tacts: 150mΩ min. e: 40N max. 1N min. 40N max.	V / 1 minute. (Detection current: 1mA)				
b) Insulation resistance	b) Insulation resistance:					
	ment part	Test result				
Contiguity						
	nd each contact	More than 100 $M\Omega$				
c) Breakdown voltage r	esistance:					

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

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	Checked by	T. Sat	Approved by	K. Tokohoshi	

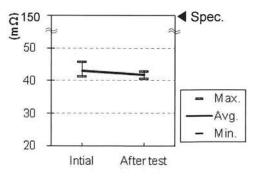
Product :	SD Memory Card Socket	
Data No. :	AXA2S73062-M-011	
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d) Contact resistance: Signal contacts

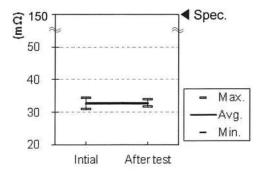


⊿Rc	[mΩ]
Avg.	0.324
Max.	3.16
Min.	-2.29

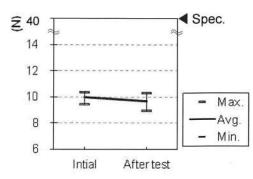
Card detection contacts



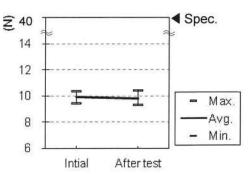
Write protect contacts



e) Card insertion force:



g) Card removal force:



Judgment

No problems were observed.

Date: April 05, 2011 HONDA TSUSHIN KOGYO CO., LTD.

Hydrogen sulfid	e TEST
Purpose	

Confirm characteristics of hydrogen sulfide in accordance with spec.

REPORT

Sample

SD Memory card socket (Applicable to SDIO S-type, Standard type,) Stand-off 0mm (With the function of card jump-out prevention) <AXA2S73062-M> (n=5)

Test condition

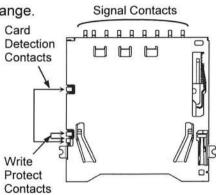
Concentration: 3ppm Temperature: +40 degrees C Humidity: 80%RH Exposure condition: Mating card

Criteria

- After 96 hours exposure
- a) Appearance: There is no deforming, camber and crack of molded parts.
- b) Insulation resistance: 100 MΩ min. (at D.C. 500 V)
- c) Breakdown voltage resistance: A.C. 500 V / 1 minute. (Detection current: 1mA)

d) Contact resistance:

Signal contacts: After test 40m
maximum change. Card detection contacts: 150mQ min. Write protect contacts: 150mQ min.



Test result

a) Appearance: There was no deforming, camber and crack of molded parts.

b) Insulation resistance:

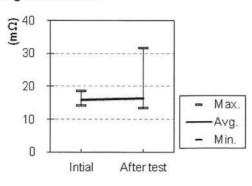
Measurement part	Test result	
Contiguity terminals	More than 100 M Ω	
Between shell and each contact	More than 100 Mg	

c) Breakdown voltage resistance:

Measurement part	Test result
Contiguity terminals	There are no short and damage at A.C.
Between shell and each contact	500 V for 1 minute.

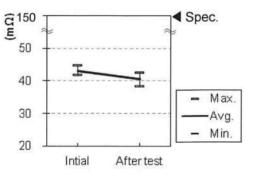
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d) Contact resistance: Signal contacts

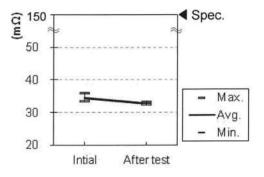




Card detection contacts



Write protect contacts



Judgment

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